### TTTC IN GENERAL

**PURPOSE:** The Test Technology Technical Council is a volunteer professional organization sponsored by the IEEE Computer Society. The goals of TTTC are to contribute to members' professional development and advancement and to help them solve engineering problems in electronic test, and help advance the state-of-the-art. In particular, TTTC aims at facilitating the knowledge flow in an integrated manner, to ensure overall quality in terms of technical excellence, fairness, openness, and equal opportunities.

**MEMBERSHIP:** Membership is open to all individuals interested in test engineering at a professional level.

**DUES:** There are NO dues for TTTC membership and no parent-organization membership requirements.

**BENEFITS:** The TTTC members benefit from personal association with other test professionals. They may have the opportunity to be involved on a wide range of committees. They receive appropriate and updated information and announcements. There are substantial reductions in fees for TTTC-sponsored meetings and tutorials for members of IEEE and/or IEEE Computer Society.

### TTTC ACTIVITIES

**TECHNICAL MEETINGS:** To spread technical knowledge and advance the state-of-the art, TTTC sponsors many well-known conferences and symposia and holds numerous regional and topical workshops worldwide.

**STANDARDS:** TTTC initiates, nurtures and encourages new test standards. TTTC-initiated Working Groups have produced numerous IEEE standards, including the 1149 series used throughout the industry.

**TECHNICAL ACTIVITIES:** TTTC sponsors a number of Technical Activity Committees (TACs) that address emerging test technology topics and guide a wide range of activities.

**TUTORIALS and EDUCATION:** TTTC sponsors a comprehensive Test Technology Educational Program (TTEP). This program provides opportunities for design and test professionals to update and expand their knowledge base in test technology, and to earn official accreditation from IEEE TTTC, upon the completion of four full day tutorials proposed by TTEP.

### TTTC CONTACT

**TTTC On-Line:** The TTTC Web Site at http://tab.computer.org/tttc offers samples of the TTTC Newsletter, information about technical activities, conferences, workshops and standards, and links to the Web pages of a number of TTTC-sponsored technical meetings.

**Becoming a MEMBER:** Becoming a TTTC member is extremely simple. You may either contact by phone or e-mail the TTTC office, or fill out and submit a TTTC application form, or visit the membership section of the TTTC web site.

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TTTC-Sponsored Technical Meetings in 2013
For the most current information, please visit the TTTC website (http://tab.computer.org/tttc) or TTTC Events website (http://www.tttc-events.org)

3/18-3/22 Design, Automation and Test in Europe (DATE), Grenoble, France
E. Macii

3/26-3/27 Workshop on Silicon Errors in Logic - System Effects (SELSE), Stanford U., CA, USA
V. Sridharan

4/3-4/5 Latin American Test Workshop (LATW), Cordoba, Argentina
R. Velazco, Y. Zorian

4/8-4/10 Design & Diagnosis of Electronic Circuits & Systems Symposium (DDECS), Karlovy Vary, Czech
L. Sekanina

4/29-5/2 VLSI Test Symposium (VTS), Berkeley, CA, USA
R. Renovell

5/28-6/1 European Test Symposium (ETS), Avignon, France
P. Girard

6/2-6/3 Int'l Symposium on Hardware-Oriented Security and Trust (HOST), Austin, TX, USA
R. Karri

6/3 Int'l Workshop on Design for Manufacturability & Yield (DfM&Y), Austin, TX, USA
R. Aitken, Nagaraj NS

7/8-7/10 International On-Line Testing Symposium (IOLTS), Crete, Greece
M. Nicolaidis, A. Paschalis

7/10-7/11 ATE: Vision 2020, San Francisco, CA, USA
A. Khoche

9/14-9/17 East-West Design and Test Symposium (EWDTS), Rostov-on-Don, Russia
V. Hahanov, Y. Zorian

10/2-10/4 Int'l Symp. on Defect & Fault Tolerance in VLSI and Nanotechnology Systems (DFT), New York City, USA
J. Han, R. Karri

9/10-9/12 International Test Conference (ITC), Anaheim, CA, USA
G. Robert

9/11 Int'l Defect and Adaptive Testing Workshop (DAT), Anaheim, CA, USA
A. Sinha

9/12 International Silicon Debug and Diagnosis Workshop (SDD), Anaheim, CA, USA
T. McLaurin

9/12-9/13 Workshop on Testing Three-Dimensional Stacked Integrated Circuits (3D-Test), Anaheim, CA, USA
Y. Zorian

9/12-9/13 Workshop on Test & Validation of High Speed Analog Circuits (TVHSAC), Anaheim, CA, USA
A. Majumdar

10/TBD Board Test Workshop (BTW), Fort Collins, CO, USA
W. Eklow

11/18-11/22 Asian Test Symposium (ATS), Jiaosi, Yilan, Taiwan
S.-J. Wang

11/21-11/22 Workshop on RTL and High Level Testing (WRTLT), Jiaosi, Yilan, Taiwan
K.-J. Lee

12/TBD International Workshop on Microprocessor Test and Verification (MTV), Austin, TX, USA
M. Abadir

12/14-12/16 International Workshop on Design & Test, Marrakesh, Morocco
Y. Zorian, S. Hamdioui

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